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| Notice of References Cited | Application/Control No. 10/816,282 | Applicant(s)/Patent Under Reexamination CHANG, PETER L.D. | |
| | Examiner Tu-Tu Ho | Art Unit 2818 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| | A | US-6,137,134 | 10-2000 | Nakagawa, Kenichiro | 257/316 |
| | B | US-6,190,981 | 02-2001 | Lin et al. | 438/305 |
| | C | US-6,243,293 | 06-2001 | Van Houdt et al. | 365/185.14 |
| | D | US-6,831,310 | 12-2004 | Mathew et al. | 257/270 |
| | E | US-2002/0114191 | 08-2002 | Iwata et al. | 365/185.23 |
| | F | US-2004/0152245 | 08-2004 | Madurawe, Raminda U. | 438/164 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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